

Search Notes**Application/Control No.**

10/575,446

Examiner

/Yonel Beaulieu/

**Applicant(s)/Patent under
Reexamination**

TAKAMATSU ET AL.

Art Unit

3661

SEARCHED

Class	Subclass	Date	Examiner
701	51	3/21/2009	YB
	56		
	90		
477	34		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Int. Search		3/21/2009	YB

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST+Int.+Fwd/Bwd	3/21/2009	YB